



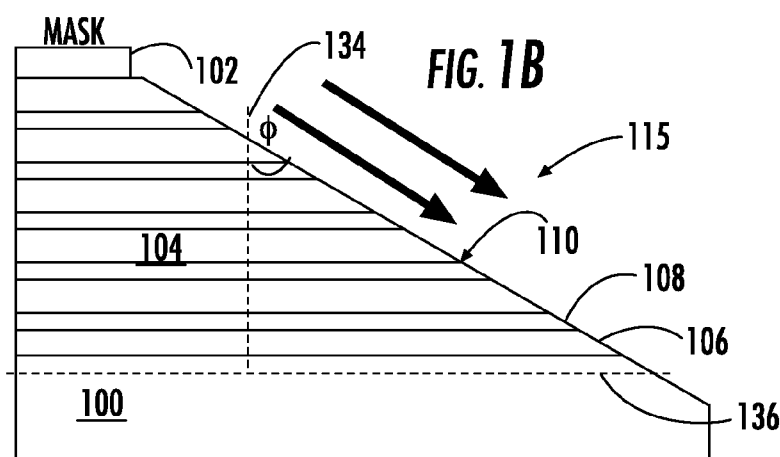
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(54) **Title:** ANGLED ION BEAM PROCESSING OF HETEROGENEOUS STRUCTURE

(57) **Abstract:** A method for fabricating a multilayer structure includes providing a mask on a device stack disposed on the substrate, the device stack comprising a first plurality of layers composed of a first layer type and a second layer type; directing first ions along a first direction forming a first non-zero angle of incidence with respect to a normal to a plane of the substrate, wherein a first sidewall is formed having a sidewall angle forming a first non-zero angle of inclination with respect to the normal, the first sidewall comprising a second plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type; and etching the second plurality of layers using a first selective etch wherein the first layer type is selectively etched with respect to the second layer type.



ANGLED ION BEAM PROCESSING OF HETEROGENEOUS STRUCTURE FIELD

[0001] The present embodiments relate to substrate processing, and more particularly, to techniques for fabricating multilayer device structures.

BACKGROUND

[0002] As semiconductor devices scale to smaller dimensions, a need has arisen to develop three dimensional structures to provide more device functionality within a given area on a substrate. Examples of these three dimensional structures include finFET logic devices as well as 3 dimensional (3D) memory devices. One example of 3D memory attracting recent interest is a type of flash memory known as a vertical NAND device or VNAND. In some particular implementations, the VNAND devices are implemented by fabricating 16, 32, or 64 layers to serve as storage elements. In one variant, in order to access different layers the VNAND device stack may be patterned with a masking element, and subsequently etched in a series of cycles through the series of layers contained in the device stack. In a given cycle, the mask size is reduced by resist trimming between successive etch operations to form a pyramidal staircase structure where the top of the pyramid may be the top device layer, and the base of the pyramid constitutes the deepest device layer exposed so contact formation can subsequently be made. This process may entail many cycles including many etch operations, because the etch operation is performed as a vertical reactive ion etching sequence configured to etch just one or a few layers in a cycle. Thus, for a 64 layer device stack, a series of 8, 16, or greater number of etch operations may be performed, as well as a like number of mask trimming operations. In addition, after performing such a large number of etch operations, the shape of such device structures may be compromised, leading to a less

reliable process. Moreover, the resist trimming operation may result in reduction in dimension of a mask element along all sides of a square or rectangular resist shape, resulting in a square pyramid device structure occupying a large projected area on the substrate. An overly large structure is produced even in the case when just two sides of the pyramid structure are to be accessed to form a memory device.

[0003] It is with respect to these and other considerations the present improvements have been needed.

SUMMARY

[0004] This Summary is provided to introduce a selection of concepts in a simplified form further described below in the Detailed Description. This Summary is not intended to identify key features or essential features of the claimed subject matter, nor is it intended as an aid in determining the scope of the claimed subject matter.

[0005] In one embodiment, a method for fabricating a multilayer structure on a substrate may include providing a mask on a device stack disposed on the substrate, the device stack comprising a first plurality of layers composed of a first layer type and a second layer type; directing first ions along a first direction forming a first non-zero angle of incidence with respect to a normal to a plane of the substrate, wherein a first sidewall is formed having a sidewall angle forming a first non-zero angle of inclination with respect to the normal, the first sidewall comprising a second plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type; and etching the second plurality of layers using a first selective etch wherein the first layer type is selectively etched with respect to the second layer type, wherein a first sidewall structure is formed having a stepped structure and defining a first average sidewall angle having a non-

zero angle of inclination with respect to the normal, wherein a stepped surface of the first sidewall structure is angled with respect to the first average sidewall angle.

[0006] In another embodiment, a method for fabricating a multilayer structure on a substrate may include providing a mask on a device stack disposed on the substrate, the device stack comprising a first plurality of layers composed of a first layer type and a second layer type; directing first ions along a first direction forming a first non-zero angle of incidence with respect to a normal to a plane of the substrate, wherein a first sidewall is formed having a sidewall angle forming a first non-zero angle of inclination with respect to the normal, the first sidewall comprising a second plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type; and forming an electrical contact to at least one layer of the first layer type along the first sidewall.

[0007] In a further embodiment, a multilayer device may include a heterogeneous device stack disposed on a substrate, the heterogeneous device stack comprising at least one layer of a first layer type and at least one layer of a second layer type; at least one sidewall defining a first average sidewall angle having a non-zero angle of inclination with respect to a normal to a substrate plane; and at least one additional sidewall defining a second average sidewall angle different from the first average sidewall angle wherein the at least one sidewall comprises a stepped structure.

BRIEF DESCRIPTION OF THE DRAWINGS

[0008] **FIGs. 1A-1D** depict a cross-section of a device structure at various instances illustrating exemplary operations involved in a method for fabricating a multilayer structure according to various embodiments of the disclosure;

[0009] FIGs. 2A-2C depict cross-sectional micrographs of exemplary device structures after processing using an angled ion beam according to embodiments of the disclosure;

[0010] FIG. 3A depicts a cross-sectional micrographs of an exemplary device structure after sequential processing using an angled ion beam and selective etching according to embodiments of the disclosure;

[0011] FIG. 3B depicts a close-up view of a portion of the device structure of FIG. 3A;

[0012] FIG. 4 depicts an exemplary process flow;

[0013] FIGs. 5A-5C depict a cross-section of a device structure at various instances illustrating exemplary operations involved in a method for fabricating a multilayer structure according to additional embodiments of the disclosure; and

[0014] FIGs. 6A-6C depict a perspective view of different device structures according to additional embodiments of the disclosure.

DETAILED DESCRIPTION

[0015] The embodiments described herein provide techniques and for fabricating multilayer structures on a substrate composed of multiple layers, where the multiple layers may be referred to herein as a "device stack." The device stack may be a heterogeneous device stack, meaning the device stack includes at least one layer of a first layer type and at least one layer of a second layer type. The first layer type generally differs from the second layer type in composition of material, or microstructure, or composition and microstructure. An example of a heterogeneous device stack may be a stack of layers where a silicon layer and an insulating layer are arranged in alternating fashion. Such an arrangement is

characteristic of vertical or 3D device structures such as the aforementioned VNAND. The embodiments are not limited in this context and may include other heterogeneous device stacks.

[0016] Various embodiments provide a treatment of a heterogeneous device stack by a novel combination of etching processes defining angled device structures, where the sides of device structures define a non-zero angle with respect to a normal (perpendicular) to a plane of the substrate. Such device structures, by virtue of the non-zero angle, may provide convenient access to a plurality of different layers within the device structure, as detailed below.

[0017] In particular embodiments, in one operation directed ion etching is provided to a masked heterogeneous device stack at a non-zero angle with respect to the normal to define an angled device structure having an angled sidewall extending through a plurality of layers of the device stack. In a subsequent operation, a selective etching process or multiple selective etching processes may be performed on the angled device structure in order to define a stepped device structure defining an angle similar to the angled device structure.

[0018] Turning now to **FIG. 1A** there is shown an initial device structure composed of a substrate 100 and device stack 104. The term "substrate" as used herein may refer to a portion of a substrate structure where other materials, layers, and so forth may be disposed. Thus, the substrate 100 of FIG. 1 forms a base structure where other materials, such as the device stack 104 may be disposed upon the base structure. In particular examples disclosed herein, a device structure may be fabricated on a substrate, where the device structure may be located in layers other than the substrate. In other examples, a device structure may be formed partially within a substrate in other examples.

[0019] In various embodiments, the device stack 104 is composed of a plurality of layers extending throughout the device stack as shown in more detail in FIG. 1B. In this example, the device stack 104 may be characterized as a heterogeneous device stack including a first layer type alternating with a second layer type, forming a sequence of layers 108 alternating with layers 106, as shown. In a particular example for fabricating a memory structure, the layers 108 may be silicon and the layers 106 may be an insulator material layer such as oxide, or alternatively the stacked layers 108 may be silicon nitride and layers 106 may be oxide. The embodiments are not limited in this context. In some examples a layer thickness of either layer, meaning layer 108 or layer 106, may range between 5 nm and 500 nm. The embodiments are not limited in this context. In other embodiments, a heterogeneous device stack may be composed of different sequences of layers, such as a sequence of three different layer types.

[0020] According to various embodiments of the disclosure the device stack 104 may be etched in a pattern in order to form a device structure defined by an angled side or angled sides of a device, where the angled sides are composed of a plurality of layers within the device stack 104. The term "angled" as used herein refers to a surface, structure, or trajectory of ions where the relevant feature forms a non-zero angle with respect to a normal to a substrate plane. In order to define such a device structure a mask 102 is disposed on the device stack 104 over a portion of the device stack, leaving an exposed portion 130 of the device stack 104. The mask 102 may be a hard mask, such as an oxide, nitride, carbon, or other material, may be a resist material, or other material known in the art. The mask 102 may be composed of a plurality of mask elements instead of just one mask feature as illustrated in FIG. 1A,. In accordance with the Cartesian coordinate system shown, in some

embodiments, a mask dimension along the X-axis, Y-axis, or X- and Y-axis may range from 5 nm to 1000 nm. The embodiments are not limited in this context.

[0021] In accordance with embodiments of the disclosure, ions may be directed to the device stack 104 to etch portions of the device stack 104 to define a device structure. The mask 102 may serve to block ions from striking protected regions 132 of the device stack 104. Thus, the mask 102 may be designed to have adequate thickness to attenuate ions according to the specie of ion, the ion energy, ion dose, and angle of incidence of ions 120. In the instance shown in FIG. 1A ions 120 are directed to the device stack 104 at a non-zero angle of incidence, shown as the angle θ with respect to a normal 134 to the plane 136 of the substrate 100, where the angle θ may vary between 15 degrees and 70 degrees in some embodiments. In various embodiments, the ions 120 may be inert gas ions (He, Ar, Kr, Xe, Rn) configured to etch the device stack 104 by physical sputtering. An advantage of using inert gas ions is providing physical etching of different layers within the device stack 104 so the different layers may not be sensitive to variations in material in the device stack, and unwanted reactions between ions 120 and material within the device stack 104 may be avoided. In some embodiments, the ion energy of ions 120 may be less than 50 KeV, and in particular embodiments may range between 1 keV and 30 KeV. The embodiments are not limited in this context.

[0022] According to particular embodiments the ions 120 may be provided by known apparatus including beamline ion implanters, compact ion beam sputtering type apparatus, or other apparatus configured to direct ions to a substrate at a non-zero angle of incidence with respect to a normal to the plane of the substrate. Turning now to the **FIG. 1B** there is shown a later instance where ions 120 have etched the device stack 104 in the exposed portion 130

so as to define a sidewall, or side 110, of an angled device structure 115 angled with respect to the normal 134. In various embodiments an angle of inclination ϕ of the side 110 may be similar to- or the same as the angle of incidence θ of the ions 120. The ion dose of ions 120 may be varied depending upon the number of layers of the device stack 104 to be etched. For example, the device stack 104 may be composed of a first plurality of layers including, for example, 64 layers, while it is targeted to etch just 32 layers. Accordingly a dose of ions 120 may be provided for etching just half of the device stack 104. In the example of device stack 104, in contrast, the entire device stack 104 has been etched to the substrate 100.

[0023] An advantage of using a tool such as a beamline ion implanter to etch the device stack 104 is control of angle of incidence. For example, the angle of incidence θ of ions 120 may be controlled to a precision of better than 1 degree in some instances, allowing for formation of a side 110 having a precisely defined angle of inclination, shown as an angle of inclination ϕ .

[0024] Turning now to **FIGs. 2A** and **2B** there are shown cross-sectional micrographs of exemplary device structures after processing using an angled ion beam according to embodiments of the disclosure. In FIG. 2A a device stack 202 having approximately 90 layers formed by alternating layers of polysilicon and silicon oxide is disposed on a substrate 200. The device stack 202 has been etched using an ion beam at an angle of incidence of approximately 30 degrees with respect to a normal (parallel to the Z-axis) to a surface of the substrate 200. An ion dose has been provided to etch 42 layers of the device stack 202, defining a side 204 of a device structure 206. In FIG. 2B a device stack 212 also having approximately 90 layers formed by alternating layers of polysilicon and silicon oxide is disposed on a substrate 210. The device stack 212 has been etched using an ion beam at an

angle of incidence of approximately 30 degrees with respect to a normal (parallel to the Z-axis) while an ion dose has been provided to etch 64 layers of the device stack 212, defining a side 214 of the resultant device structure 216. In the two cases, the respective sides, side 204 and side 214, are smooth and the microstructure exhibits no ripples or significant deformation.

[0025] **FIG. 2C** depicts a close-up view of a portion of a device stack 222 after etching via an angled ion beam at an angle of incidence of approximately 30 degrees with respect to a normal to form the device structure 226. As illustrated, the side 224 exhibits a smooth surface.

[0026] Returning now to **FIG. 1B**, at the instance shown the angled device structure 115 does not have a defined stepped structure. In some embodiments, the non-stepped structure of the angled device structure 115 in **FIG. 1B** may be adequate for formation of contacts to select layers in the angled device structure 115, such as at least one layer of layers 106.

[0027] Returning now to **FIG 1C** there is shown a further operation to define a stepped surface in the device structure 206, or angled device structure 115 of **FIG. 1B**.. In particular, the device structure 206 may be subject to a first selective etch configured to direct etching species 112 to the side 110. In various embodiments the etching species 112 may be reactive ion etching species as known in the art. In other embodiments, the etching species 112 may be provided in a selective wet chemical etch as known in the art. The etching species 112 may be designed to selectively etch the layers 106 with respect to the layers 108, meaning a first etch rate of the layers 106 is greater than a second etch rate of the layers 108. After exposure to the etching species 112, portions 106a of layers 106 are

removed, resulting in a staircase device structure 116. The staircase device structure 116 is composed of stepped surfaces or terraces 122a forming on portions 122 of layers 108 after the portions 106A are removed.

[0028] Turning now to **FIGs. 3A** and **3B**, there is shown a cross-sectional micrograph of a staircase device structure 302 fabricated according to embodiments of the disclosure. The staircase device structure 302 includes a plurality of layers 308 of a first type, alternating with a corresponding plurality of layers 310 of a second type. Accordingly, a layer of a first type and a layer of a second type may be deemed one layer pair and the staircase device structure 302 may include a plurality of layer pairs. The structure of the staircase device structure 302 may be formed by directing an angled ion beam at an angle of incidence with respect to the normal 134 to the plane 136, generating a sidewall structure shown as the side 304 having a stepped surface. The side 304 is generally defined by an average sidewall angle having a first angle of inclination ϕ with respect to the normal 134. The sidewall structure is composed of stepped surfaces, or terraces 312. The terraces 312 are angled with respect to the average sidewall angle, in other words, are oriented at a second angle of inclination different than the first angle of inclination ϕ . As viewed in **FIGs. 3A** and **3B** the second angle of inclination is more horizontally oriented, in other words, lies closer to parallel with the X-Y plane.

[0029] Returning now to **FIG 1D** there is shown a further operation involving performing a second selective etch to the staircase device structure 116. In this example the second selective etch directs etching species 114 toward the side 110. In various embodiments the etching species 114 may be reactive ion etching species or wet chemical etching species as known in the art. The etching species 114 may be designed to selectively

etch the layers 108 with respect to the layers 106, meaning an etch rate of the layers 108 is greater than an etch rate of the layers 106. Thus, in the operations illustrated in FIGs. 1C and 1D the selectivity of etching species is reversed between the operation illustrated in FIG. 1C on the one hand and the operation illustrated in FIG. 1D. In the example of a device stack where the layers 106 are polysilicon and the layers 108 are silicon oxide, the etching species 112 are designed to selectively etch polysilicon at a faster rate than silicon oxide while the etching species 114 are designed to selectively etch silicon oxide at a faster rate than polysilicon. After exposure to the etching species 114, portions 122 of layers 108 (see FIG. 1C) are removed, resulting in a stepped device structure 118. The stepped device structure 118 is composed of terraces 124 forming on portions 122 of layers 106 after the portions 122 of layers 108 are removed.

[0030] The device structure 118 may be appropriate for forming electrical contacts to at least one of the layers 106 in the regions of terraces 124. For example an electrical contact (not shown) may be formed on multiple layers 106 using a terrace 124 to serve as a contact point. Thus, the device structure 118 may serve as the basis for forming a three dimensional "staircase" type memory, such as a VNAND memory, where different memory portions are located within different layers, as known in the art. An advantage afforded by the embodiments depicted in FIGs. 1A to 1D is the ability to fabricate a staircase type device structure having large numbers of "stairs" while avoiding the need to perform a concomitantly large number of lithography operations to define the stairs as is the practice in conventional technology. For example, as generally shown in FIGs. 1A-1D and FIGs. 2A-2C, in some embodiments a staircase type device structure having 64 different layers may be fabricated using just one mask while avoiding performing multiple mask trim

operations. This simplified process may largely reduce the cost and complexity of forming 3D device structures having multiple layers.

[0031] FIG. 4 depicts an exemplary process flow 400 comprising exemplary operations involved in a method for forming a device structure according to embodiments of the disclosure. At block 402 a substrate structure is provided, the substrate structure defined by a substrate plane and composed of a heterogeneous device stack including a first plurality of layers having a first layer type and a second layer type. Layers of the first layer type may be arranged in alternating fashion with layers of the second layer type.

[0032] At block 404 a mask is provided on the heterogeneous device stack. The mask may define a plurality of masked regions and a plurality of exposed regions on the surface of the heterogeneous device stack. The mask may be composed of known mask materials including hard mask materials or resist materials.

[0033] At block 406 first ions are directed to the device stack at a non-zero angle of incidence with respect to normal to a substrate plane. For example, the layers of the plurality of layers may be arranged to lie parallel to the substrate plane so the non-zero angle of incidence forms a non-zero angle of incidence with respect to a normal to a plane of the layers also. In some embodiments, the first ions may be composed of inert gas ions configured to etch the device stack by physical sputtering.

[0034] At block 408 the first ions are used to etch a second plurality of layers of the heterogeneous device stack to form a device structure having a side forming a non-zero angle of inclination with respect to the normal. In some examples, the angle of inclination of the device structure may be equal to the angle of incidence of the first ions. The second plurality of layers may be the same as the first plurality of layers, but may also be composed of fewer

layers than the first plurality of layers. In some embodiments, the block 406 and block 408 may constitute part of the same operation of directing first ions toward a heterogeneous device stack.

[0035] At block 410 the second plurality of layers is etched using a first selective etch wherein the first layer type is selectively etched with respect to the second layer type. In various embodiments the first selective etch may be a reactive ion etch or alternatively a wet chemical etch. The first selective etch may in particular etch just portions of layers of the first layer type where the layers of the first layer type are exposed along the side of the device stack.

[0036] At block 412 the second plurality of layers is etched using a second selective etch wherein the second layer type is selectively etched with respect to the first layer type. In various embodiments the second selective etch may be a reactive ion etch or alternatively a wet chemical etch. The second selective etch may in particular etch just portions of layers of the second layer type where the layers of the first layer type are exposed along the side of the device stack.

[0037] In further embodiments a staircase device structure may be fabricated using just one exposure of a device stack to angled ions directed at a non-zero angle of incidence with respect to a normal to a plane of a substrate. The exposure to angled ions may be followed by just one selective etch operation configured to selectively remove material from a first layer type with respect to a second layer type. For example, returning to FIGs. 1A to 1C, in one embodiment, the layers 108 may be polysilicon and layers 106 may be oxide. Accordingly, the operations depicted in FIGs. 1A to 1C may be performed while omitting the second selective etch operation shown in FIG. 1D. In this example, the staircase device

structure 116 may be composed of terraces 122a where the terraces 122a are made of polysilicon surfaces to be contacted by an electrically conductive contact (not shown) formed in a subsequent operation. The width of the terraces 122a along a direction parallel to the Y-axis may be less than the width of terraces 124 formed in the process shown in FIG. 1D, but may be adequate for serving as contact structures nonetheless.

[0038] In additional embodiments a multi-layer device structure may be formed on a substrate, where the multi-layer device structure has multiple sides angled with respect to a normal to a plane of the substrate. **FIGs. 5A to 5C** depict a cross-section of a device structure at various instances, illustrating exemplary operations involved in a method for fabricating a multilayer device structure according to additional embodiments of the disclosure. The sequence of operations may be used, for example, to form a novel VNAND device structure having two sides for forming contacts to different layers of a device. In FIG. 5A there is shown a substrate 502 supporting the device stack 506 is disposed on the substrate 502. The device stack 506 includes a plurality of layers where a first layer type 540 is arranged in alternating fashion with a second layer type 542. The device stack 506 may be exposed to ions 508 when a mask 504 is disposed on a portion of the device stack 506. The ions 508, for example, inert gas ions, are directed at an angle of incidence θ_i with respect to the normal 134 as generally described above with respect to FIG. 1A. The ions 508 as a result may etch the device stack 506 to form the device structures 510, as illustrated. In particular sides 512 of the device structures 510 may form having an angle of inclination ϕ_i with respect to normal 134.

[0039] In the example of FIG. 5A, a final target structure 514 for a device to be formed is illustrated in the dashed lines. After the operation illustrated in FIG. 5A, the

sides 512 match the structure of the left side of the final target structure 514 to be formed. As is apparent from FIG. 5A, undercut sides 516 are formed on the right sides of device structure extending parallel to the sides 512 due to the etching of the ions 508. In order to accommodate the ability to generate the final target structure 514, the mask 504 extends a greater distance along the Y-axis beyond the dimensions of the top of the final target structure 514.

[0040] Turning now to FIG. 5B there is shown a subsequent etching operation, performed by directing ions 522 toward the substrate 502 along a different direction forming an angle of incidence θ_2 with respect to the normal 134. In one example, the angle of incidence θ_2 may, but need not, have the same absolute value as θ_1 with respect to normal 134. In particular embodiments, the angle of incidence and angle of incidence may be symmetrical with respect to a plane defined by the normal 134 parallel to the X-Z plane. In order to etch portions 526 of the device stack 506, the mask 504 may be etched back using known trim processes in order to form the mask 520, configured to expose the portions 526. In addition, a second mask, mask 524, may be provided to mask the sides 512 in order to prevent etching by the ions 522. The mask 524 may be a resist mask in some embodiments or may be a hard mask. The ions 522 may then etch the device stack 506 in exposed regions, meaning portions 526, as shown in FIG. 5b.

[0041] Turning now to FIG. 5C, there is shown a device structure 530 formed after etching by the ions 522 is complete. In this example, the device structure 530 includes sides 512 having an angle of inclination ϕ_1 with respect to the normal 134 and sides 532 having an angle of inclination ϕ_2 with respect to the normal 134. Subsequently, selective etching of the device structure 530 may be performed as described with respect to FIGs. 1C

and 1D, for example, resulting in a staircase device structure suitable for forming contacts to different "stairs" of the staircase.

[0042] In summary, the present embodiments provide novel techniques for forming devices structures on a substrate such as multilayer devices where at least one side is to form a non-zero angle with respect to a normal to a plane of the substrate. Various embodiments provide the ability to form a staircase type of device structure suitable for use as a vertical memory such as VNAND, where 32, 64, or a greater number of stairs may be fabricated using just one mask operation and directed ions to form an angled side of the device structure extending through the targeted number of layers.

[0043] The present embodiments also provide the ability to tailor the angle of inclination of a side or sides of a device structure by careful control of an ion beam, including a parallel beam of ions at any targeted angle of incidence. For example, staircase device structures having an angle of inclination as small as 15 degrees with respect to normal may be easily fabricated according to the present embodiments. This device structure contrasts with known technology, where a staircase type structure having an angle of inclination is approximately 60 degrees may be generated, for example. An advantage of providing steeper device sides (smaller angle of inclination) is the ability to pack devices closer together within a given footprint defined in the X-Y plane of a substrate.

[0044] A further advantage afforded by the present embodiments is the ability to form angled sides of a multilayer device structure on just those sides of the device structure needed for providing access to the different layers of the multilayer device. For example, in known staircase type device structures for use in VNAND, a pyramidal structure is formed having four angled sides as an inevitable byproduct of the multi-operation processing where multiple

mask trim operations are performed. Formation of four angled sides is the case even given when contacts may be formed on just two opposing sides of the pyramidal device structure. As exemplified in FIGs. 1A to 1D and 5A to 5C for example, the present embodiments provide a device structure where just one or two sides may be angled, while the other sides may be vertical in principle. This structure allows for further compactness in arrangement of neighboring device structures since device structures may be more closely packed along a direction perpendicular to the vertical sidewalls (such as the X-axis in the FIGs).

[0045] More generally, in accordance with the present embodiments, a multilayer device may include a heterogeneous device stack disposed on a substrate, where the heterogeneous device stack includes at least one layer of a first layer type and at least one layer of a second layer type. The multilayer device further may have at least one sidewall defining a first average sidewall angle having a non-zero angle of inclination with respect to a normal to a substrate plane, and at least one additional sidewall defining a second average sidewall angle different from the first average sidewall angle. In some examples, the multilayer device may be formed so the second average sidewall angle is parallel to the normal. Thus, the multilayer device may have at least one "vertical" sidewall and at least one angled sidewall having a stepped structure for use for contacting a layer or layer of the multilayer device.

[0046] FIGs. 6A to 6C depict further device structures highlighting some of the aforementioned advantages. In FIG. 6A there is shown a device structure 600 showing a staircase type device having angled sides on two opposing sides of the device structure 600. In FIG. 6B there is shown a device structure 610 showing a staircase type device having angled sides on two opposing sides of the device structure 610. In this example the angle of

inclination is arranged to generate steep sides of the device structure 610. In FIG. 6C there is shown an example of a two dimensional array 620 of the device structure 610, showing the ability to achieve a close packing of adjacent device structures.

[0047] Moreover, an angle of inclination may be varied between different sides of a device structure by varying the angle of incidence for ions used to treat the different sides. In addition, the present embodiments cover device structures, such as staircase devices, where a different number of layers may be exposed on a first side staircase as opposed to a second staircase.

[0048] In an additional embodiment a method of forming a staircase device may include providing a mask on a device stack disposed on the substrate, the device stack comprising a first plurality of layers composed of a first layer type and a second layer type. The method may also include directing first ions along a first direction forming a first non-zero angle of incidence with respect to a normal to a plane of the substrate, wherein a first sidewall is formed having a sidewall angle forming a first non-zero angle of inclination with respect to the normal. The first sidewall may comprise a second plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type. The method may also include selectively etching the first layer type with respect to the second layer type, wherein a first sidewall structure is formed having a stepped structure comprising a stepped surface of at least one layer of the second layer type. Additionally, the method may include forming an electrical contact to the at least one layer on the stepped surface.

[0049] Finally, the present embodiments cover techniques used to form any multilayer device structure having angled sidewalls beyond the applications of the present

embodiments highlighted herein with respect to VNAND.

[0050] In sum, the present embodiments provide multiple advantages over known fabrication techniques for fabricating vertical or 3D device structures, where multiple successive mask treatments may be applied in order to define an angled device structure. For one, the complexity of operations may be advantageously reduced by eliminating the aforementioned multiple mask treatments. For another, total cost of processing may be advantageously reduced by reducing tool use and materials use.

[0051] The present disclosure is not to be limited in scope by the specific embodiments described herein. Indeed, other various embodiments of and modifications to the present disclosure, in addition to those described herein, will be apparent to those of ordinary skill in the art from the foregoing description and accompanying drawings. Thus, such other embodiments and modifications are intended to fall within the scope of the present disclosure. Furthermore, the present disclosure has been described herein in the context of a particular implementation in a particular environment for a particular purpose, yet those of ordinary skill in the art will recognize the usefulness is not limited thereto and the present disclosure may be beneficially implemented in any number of environments for any number of purposes. Thus, the claims set forth below are to be construed in view of the full breadth and spirit of the present disclosure as described herein.

What is claimed is:

1. A method for fabricating a multilayer structure on a substrate, comprising:
providing a mask on a device stack disposed on the substrate, the device stack comprising a first plurality of layers composed of a first layer type and a second layer type;
directing first ions along a first direction forming a first non-zero angle of incidence with respect to a normal to a plane of the substrate, wherein a first sidewall is formed having a sidewall angle forming a first non-zero angle of inclination with respect to the normal, the first sidewall comprising a second plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type; and
etching the second plurality of layers using a first selective etch wherein the first layer type is selectively etched with respect to the second layer type, wherein a first sidewall structure is formed having a stepped structure and defining a first average sidewall angle having a non-zero angle of inclination with respect to the normal, wherein a stepped surface of the first sidewall structure is angled with respect to the first average sidewall angle.
2. The method of claim 1, further comprising etching the second plurality of layers using a second selective etch wherein the second layer type is selectively etched with respect to the first layer type.
3. The method of claim 2, wherein the etching the second plurality of layers using the first selective etch comprises performing a first reactive ion etch to etch the first layer type along the normal, and wherein the etching the second plurality of layers using the second

selective etch comprises performing a second reactive ion etch different from the first reactive ion etch to etch the second layer type along the normal.

4. The method of claim 1, further comprising:

directing second ions along a second direction different than the first direction, the second direction forming a second non-zero angle of incidence with respect to the normal, wherein a second sidewall is formed defining a second average sidewall angle having a non-zero angle of inclination with respect to the normal, the second sidewall comprising a third plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type; and

etching the third plurality of layers using a third selective etch wherein the first layer type is selectively etched with respect to the second layer type, wherein a second sidewall structure is formed having a stepped structure and defining a second average sidewall angle having a non-zero angle of inclination with respect to the normal, wherein a stepped surface of the second sidewall structure is angled with respect to the second average sidewall angle.

5. The method of claim 1, wherein the first ions comprise ions having an energy less than 50 KeV.

6. The method of claim 1, wherein the device stack comprises alternating layers comprising a silicon layer and insulator material layer.

7. The method of claim 1, wherein the first direction forms an angle of incidence of between 15 degrees and 70 degrees with respect to the normal.
8. The method of claim 1, wherein the first layer type is arranged in alternating fashion with the second layer type.
9. A method for fabricating a multilayer structure on a substrate, comprising:
 - providing a mask on a device stack disposed on the substrate, the device stack comprising a first plurality of layers composed of a first layer type and a second layer type;
 - directing first ions along a first direction forming a first non-zero angle of incidence with respect to a normal to a plane of the substrate, wherein a first sidewall is formed having a sidewall angle forming a first non-zero angle of inclination with respect to the normal, the first sidewall comprising a second plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type; and
 - forming an electrical contact to at least one layer of the first layer type along the first sidewall.
10. The method of claim 9, further comprising:
 - etching the second plurality of layers using a first selective etch wherein the second layer type is selectively etched with respect to the first layer type, wherein a first sidewall structure is formed having a stepped structure and defining a first average sidewall angle having a non-zero angle of inclination with respect to the normal, wherein the at least one

layer of the first layer type comprises a stepped surface angled with respect to the first average sidewall angle, and wherein the electrical contact is formed on the stepped surface.

11. The method of claim 10, further comprising etching the second plurality of layers using a second selective etch wherein the first layer type is selectively etched with respect to the second layer type.

12. The method of claim 10, further comprising:

directing second ions along a second direction different than the first direction, the second direction forming a second non-zero angle of incidence with respect to the normal, wherein a second sidewall is formed defining a second average sidewall angle having a non-zero angle of inclination with respect to the normal, the second sidewall comprising a third plurality of layers from at least a portion of the first plurality of layers and composed of the first layer type and second layer type; and

forming a second electrical contact to at least one layer of the first layer type along the second sidewall.

13. A multilayer device, comprising:

a heterogeneous device stack disposed on a substrate, the heterogeneous device stack comprising at least one layer of a first layer type and at least one layer of a second layer type;

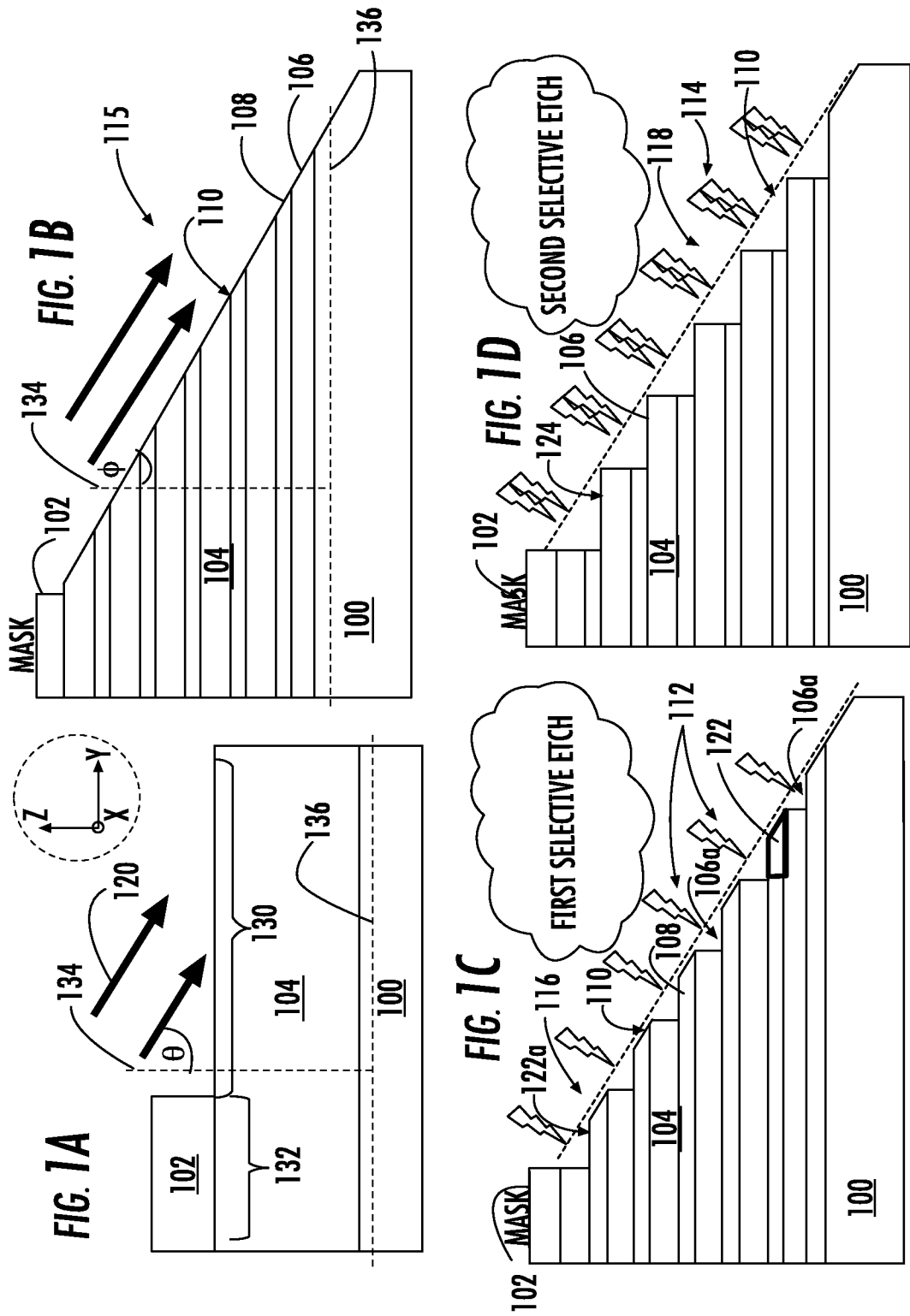
at least one sidewall defining a first average sidewall angle having a non-zero angle of inclination with respect to a normal to a substrate plane; and

at least one additional sidewall defining a second average sidewall angle different from the first average sidewall angle,

wherein the at least one sidewall comprises a stepped structure.

14. The multilayer device of claim 13, wherein the second average sidewall angle is parallel to the normal.

15. The multilayer device of claim 13, wherein the heterogeneous device stack comprises a VNAND device.



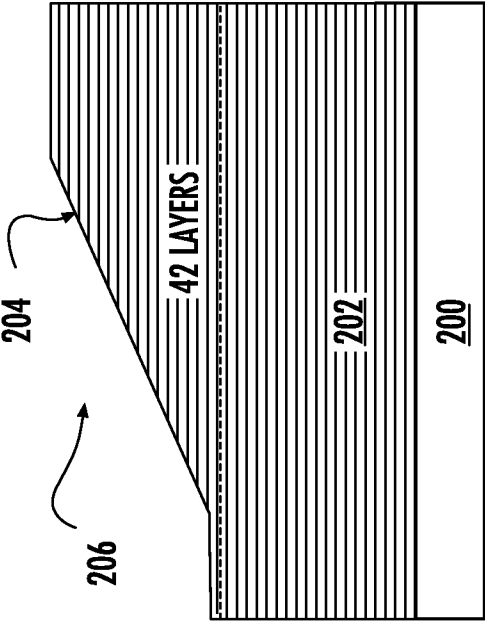


FIG. 2A

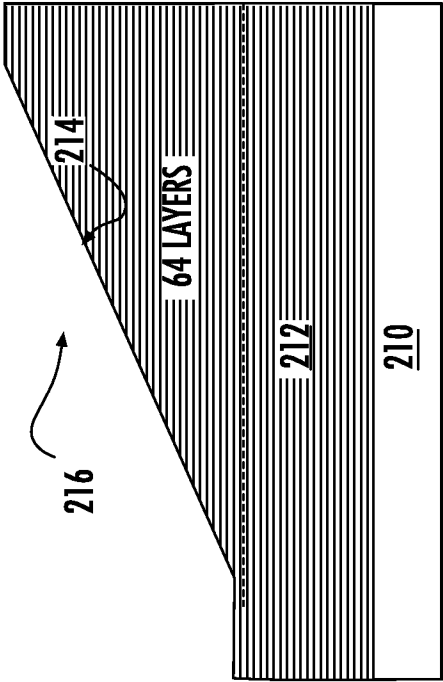


FIG. 2B

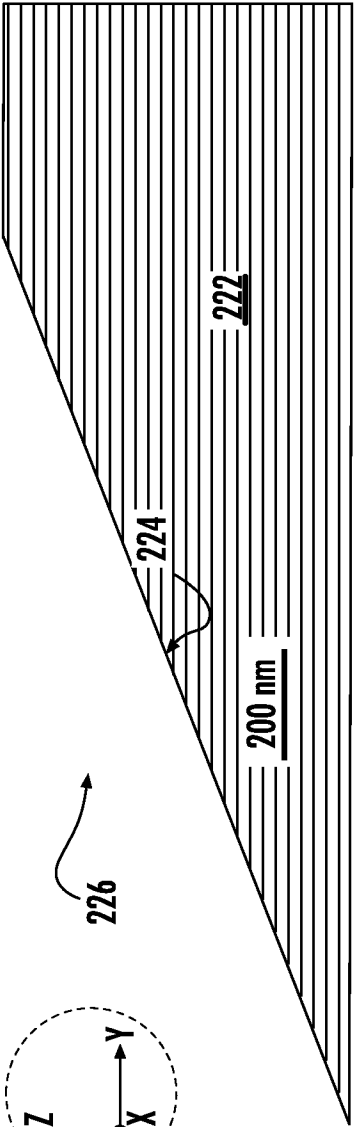


FIG. 2C

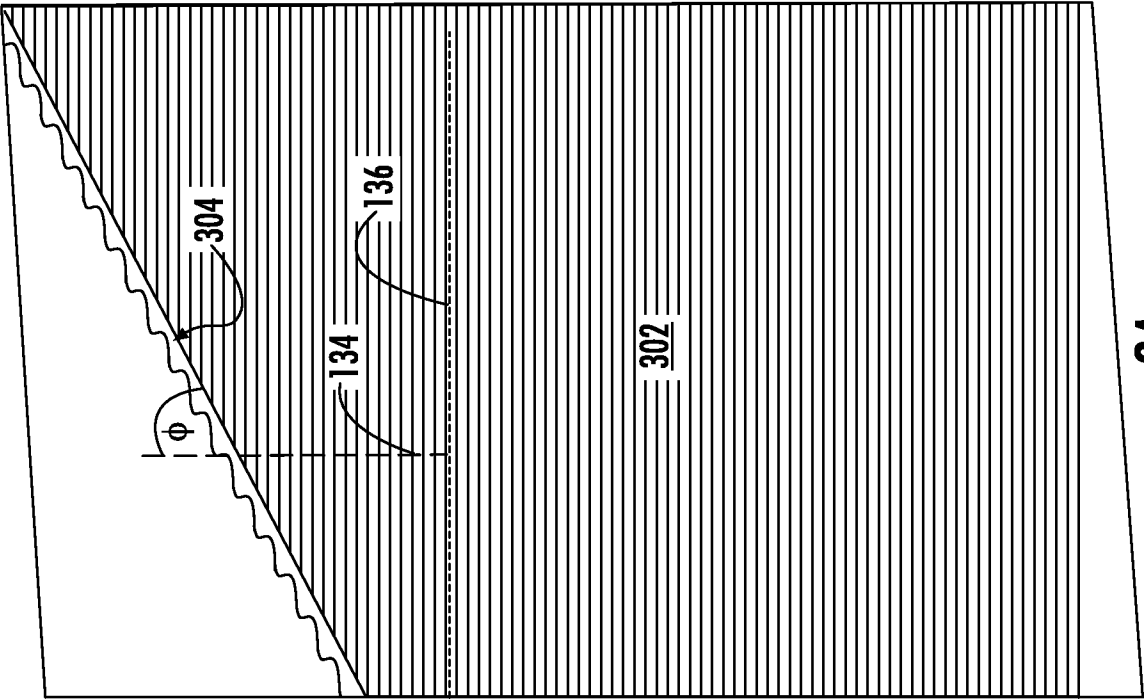


FIG. 3A

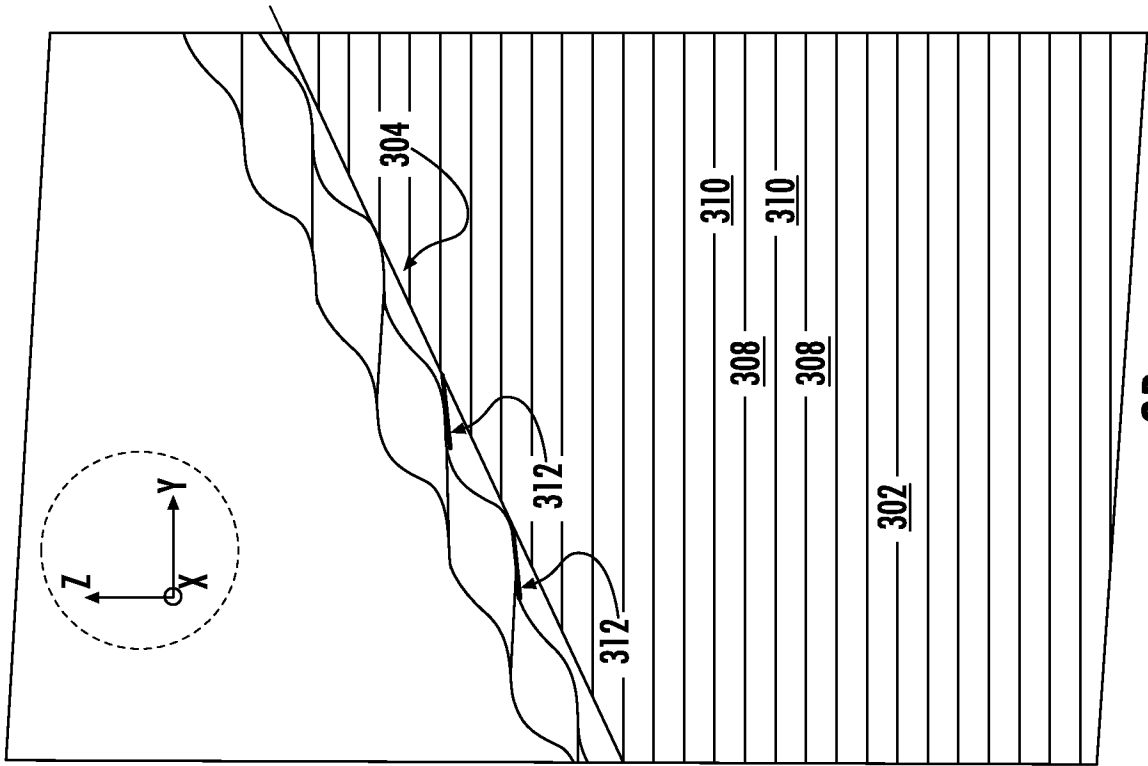


FIG. 3B

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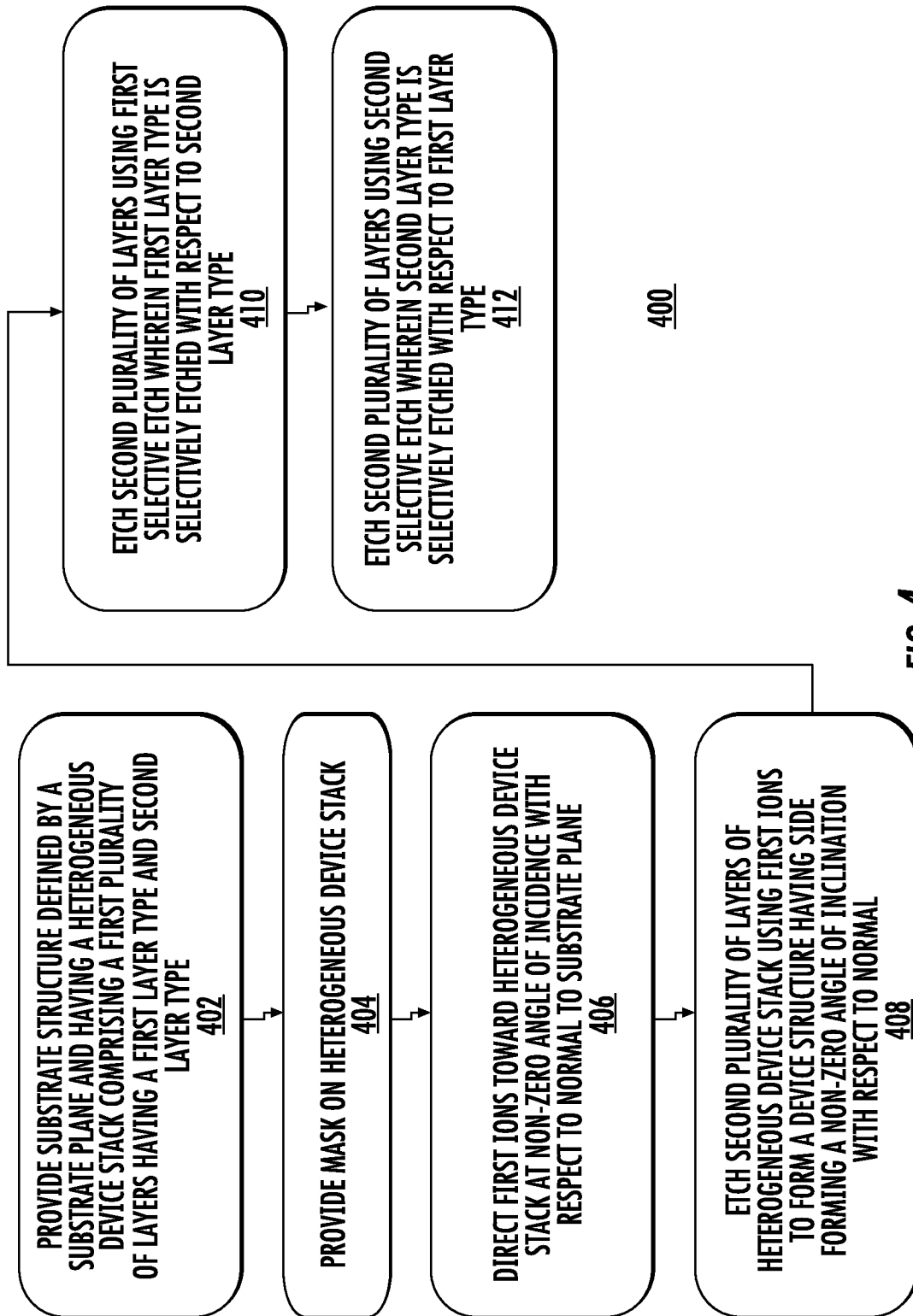


FIG. 4

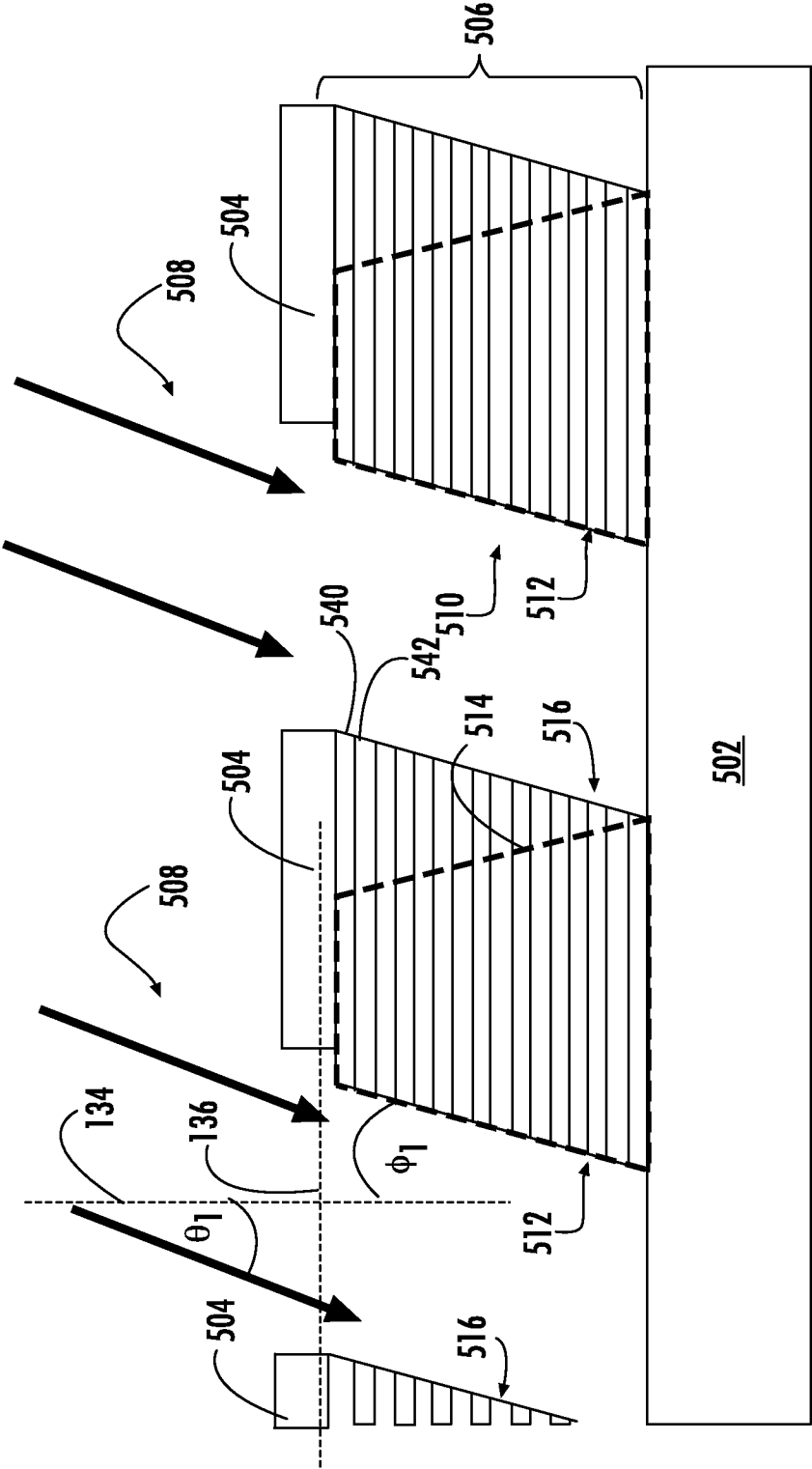


FIG. 5A

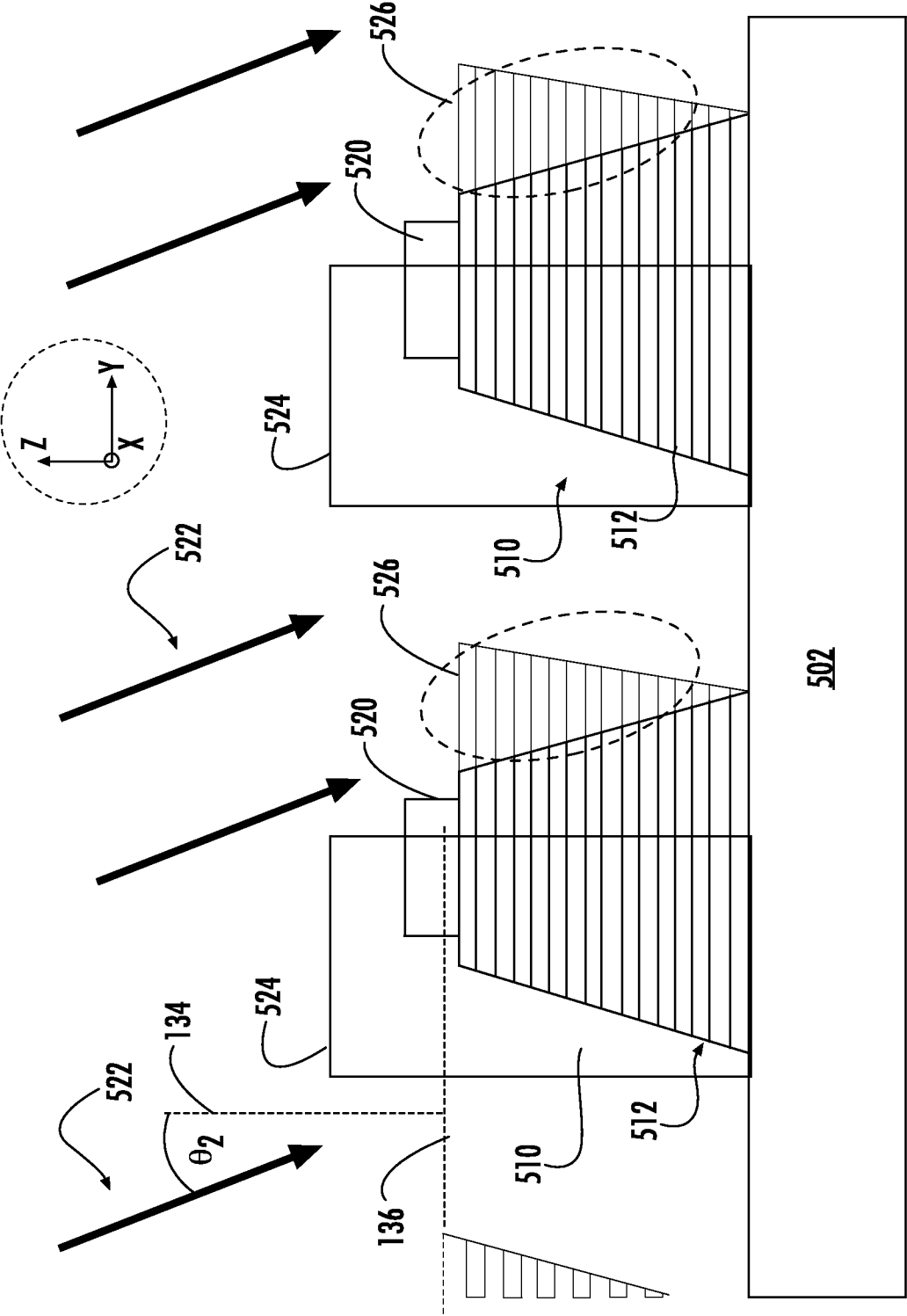
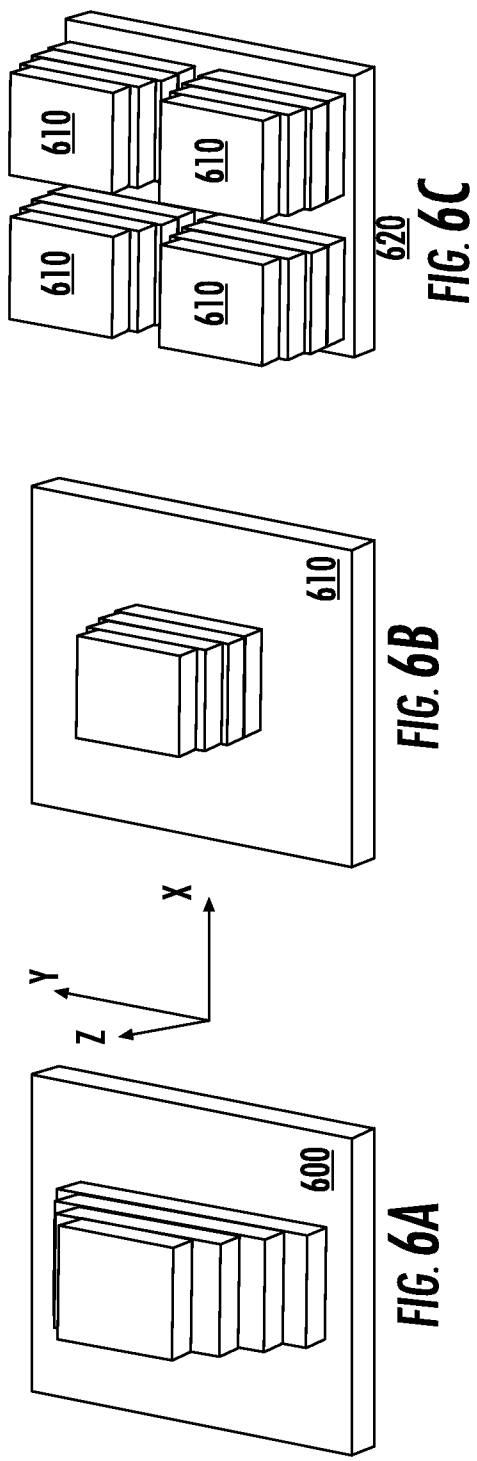
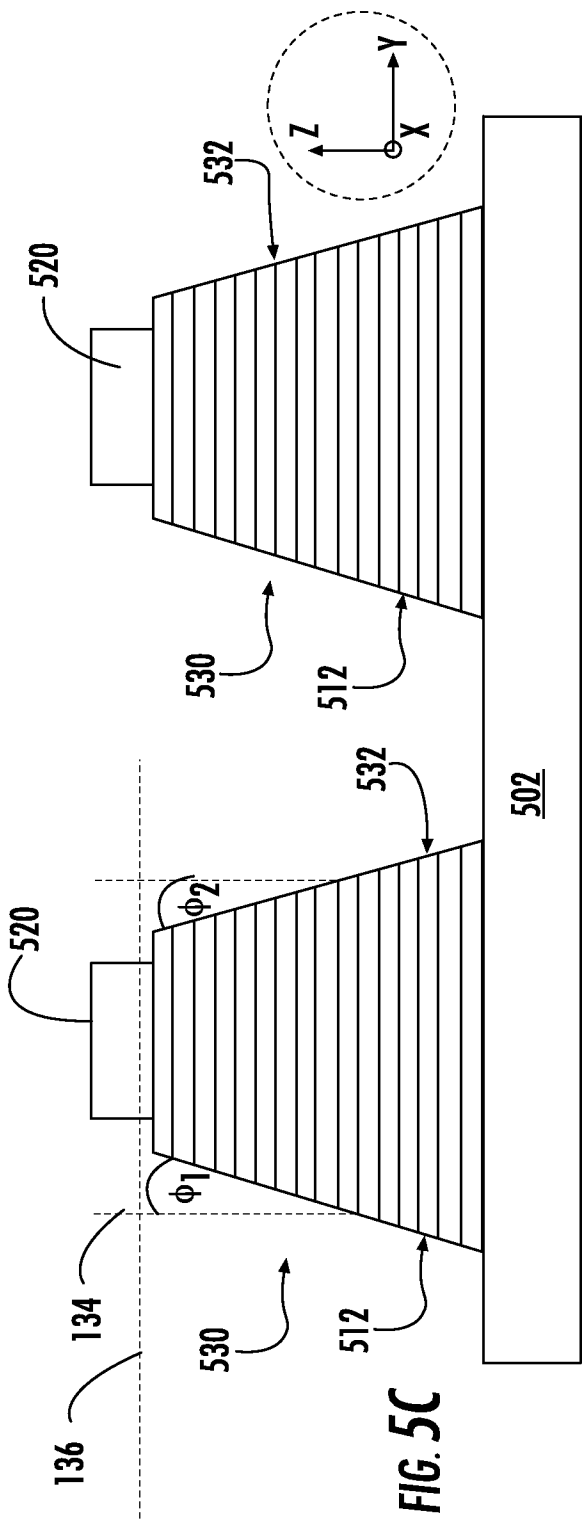


FIG. 5B



A. CLASSIFICATION OF SUBJECT MATTER**H01L 27/115(2006.01)i, H01L 21/265(2006.01)i**

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

H01L 27/115; H01L 21/768; H01L 21/308; H01L 23/528; H01L 21/8247; H01L 21/283; H01L 21/265

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Korean utility models and applications for utility models

Japanese utility models and applications for utility models

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

eKOMPASS(KIPO internal) & Keywords: multilayer, etching, ion, angle, step

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	KR 10-1044019 B1 (HYNIX SEMICONDUCTOR INC.) 24 June 2011 See abstract, paragraphs [0042]-[0059] and figures 4a-4e.	13-15
A		1-12
A	US 2014-0329379 A1 (SAMSUNG ELECTRONICS CO., LTD.) 06 November 2014 See abstract, paragraphs [0077]-[0117] and figures 13A-18E.	1-15
A	KR 10-2011-0015338 A (HYNIX SEMICONDUCTOR INC.) 15 February 2011 See abstract, paragraphs [0030]-[0053] and figures 2a-2e.	1-15
A	US 2014-0106569 A1 (JUNG-IK OH et al.) 17 April 2014 See abstract, paragraphs [0050]-[0083] and figures 2-13.	1-15
A	US 2013-0341798 A1 (MICRON TECHNOLOGY, INC.) 26 December 2013 See abstract, paragraphs [0025]-[0043] and figures 2-10.	1-15



Further documents are listed in the continuation of Box C.



See patent family annex.

* Special categories of cited documents:

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"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art

"&" document member of the same patent family

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25 February 2016 (25.02.2016)

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INTERNATIONAL SEARCH REPORT

Information on patent family members

International application No.

PCT/US2015/062905

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